

DEVICE AND METHOD OF CORRECTING EXPOSURE DEFECTS IN  
PHOTOLITHOGRAPHY

Hickman, Craig A.

Appl. No.: Unassigned Atty Docket: MICRON.100C1

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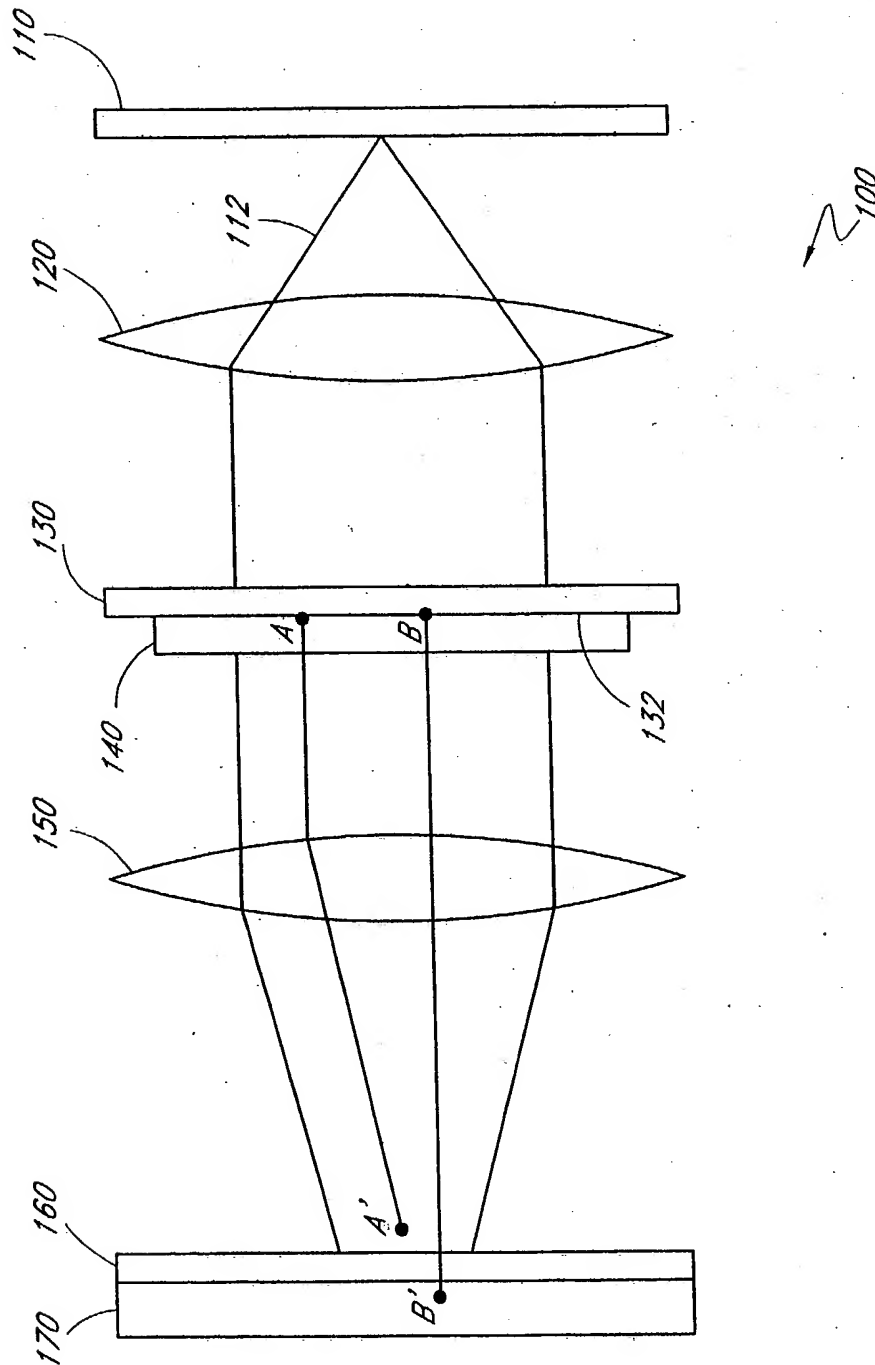


FIG. 1  
(PRIOR ART)

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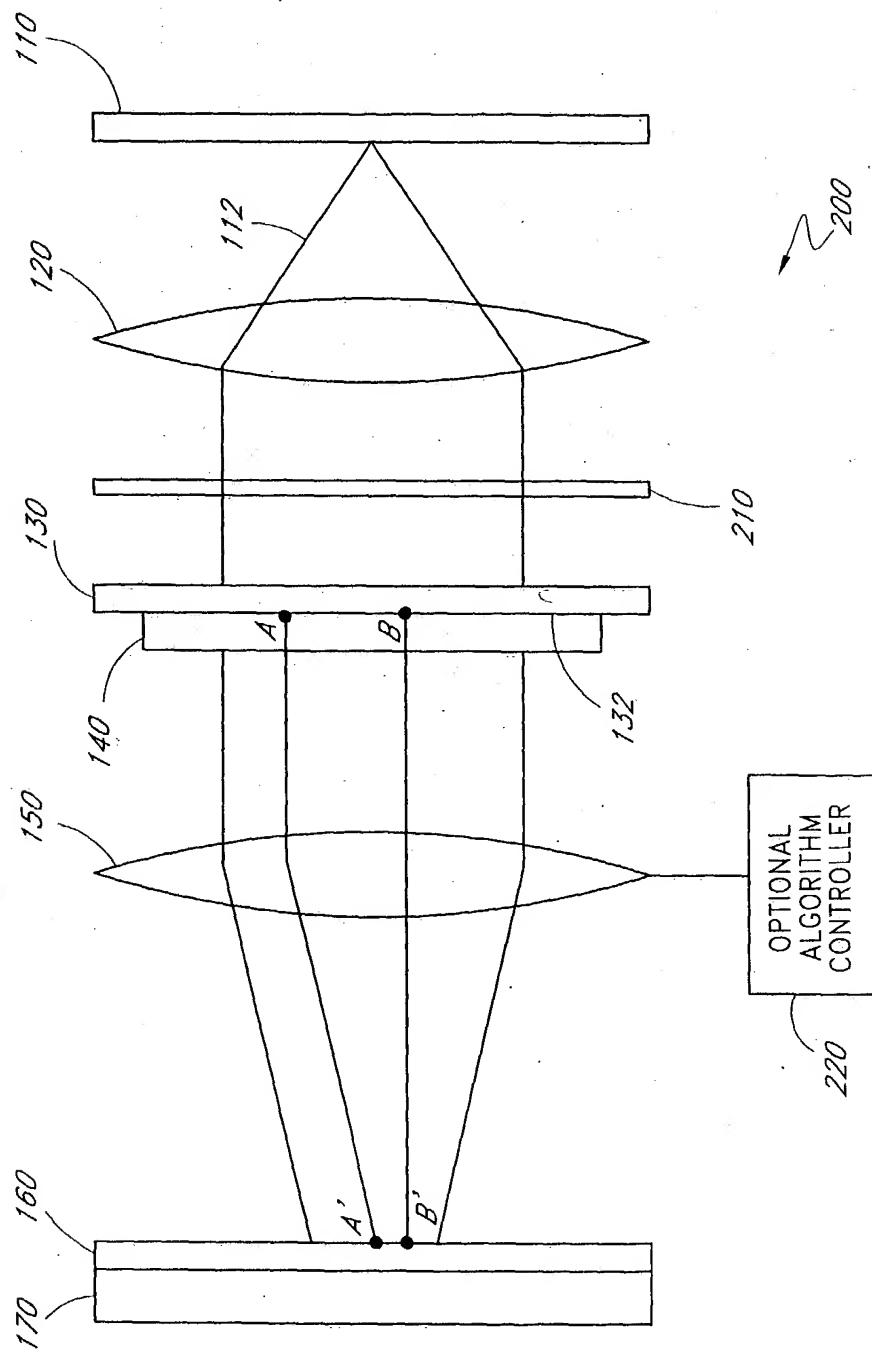


FIG. 2

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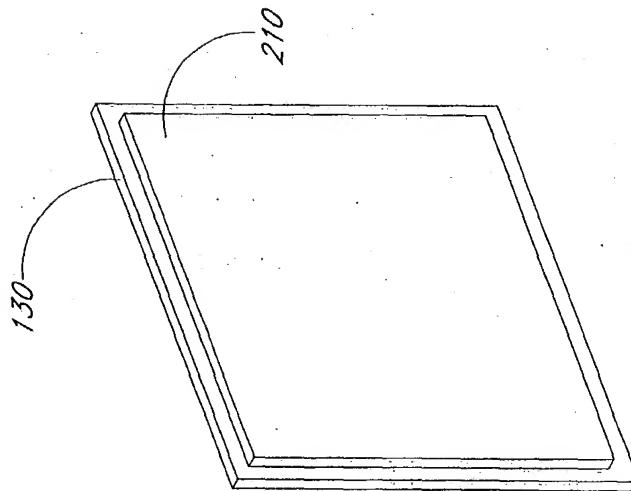


FIG. 3

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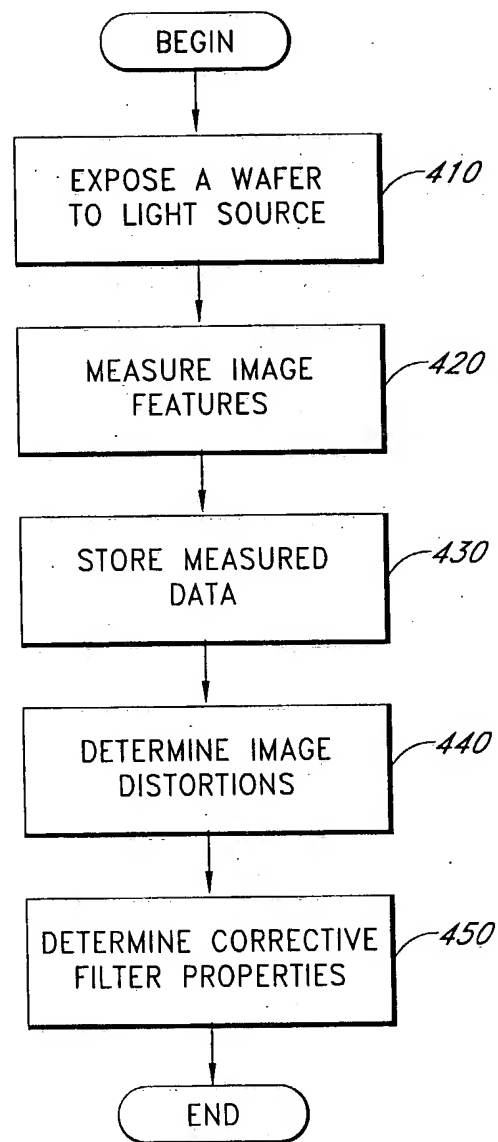


FIG. 4

DEVICE AND METHOD OF CORRECTING EXPOSURE  
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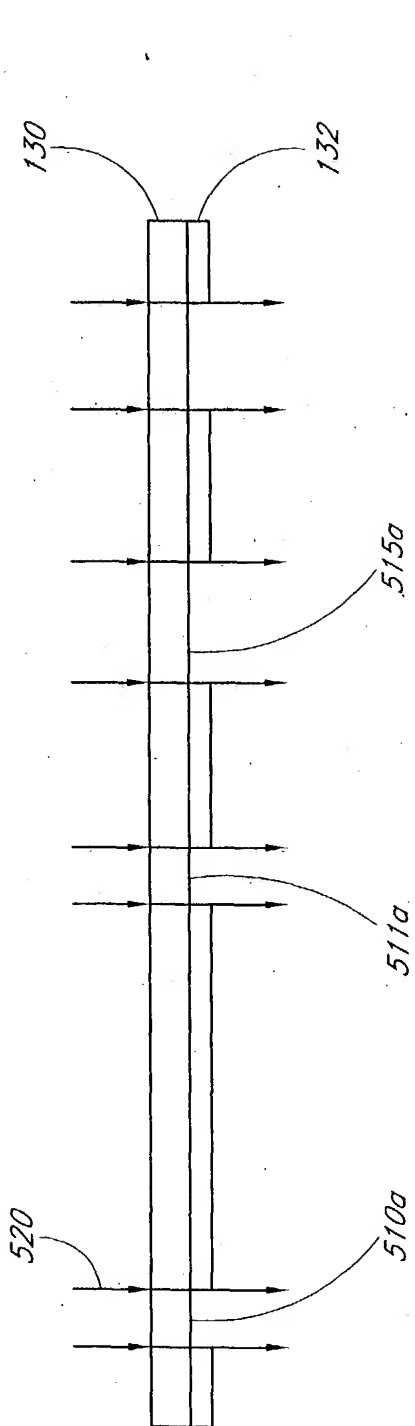


FIG. 5A

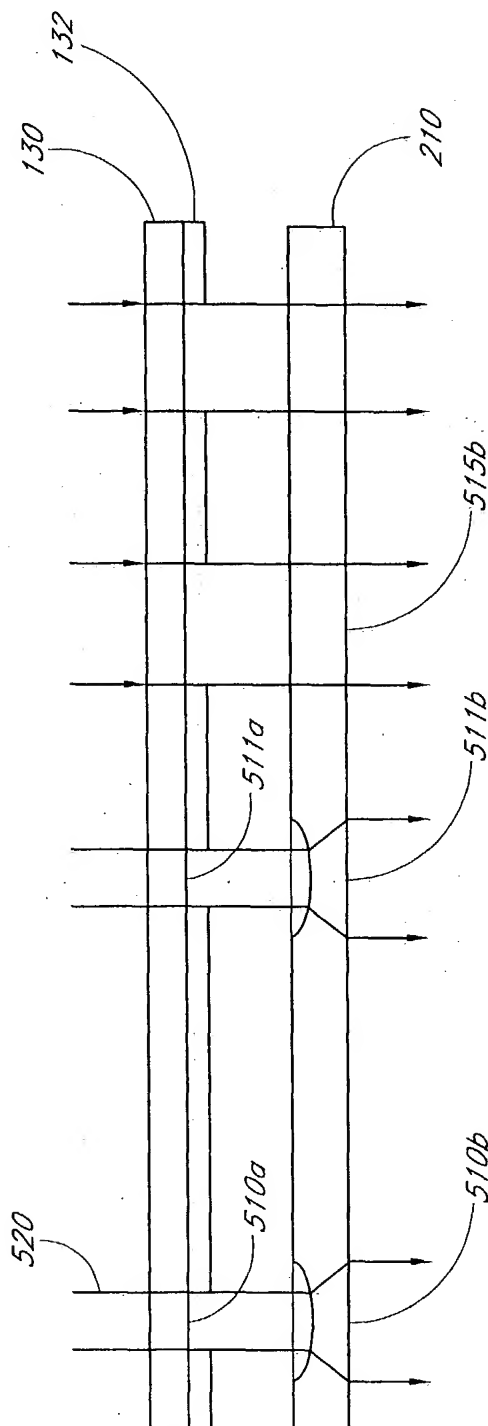


FIG. 5B